

2020년 2월 14일(금), 15:45~17:30

Room C (사파이어 I, 5층)

**H. Display and Imaging Technologies 분과**  
**[FC3-H] TFTs & Display Technology**

<b>FC3-H-1</b> 15:45~16:15	<b>[초청]</b> <b>Low Dimensional Semiconductors Based Optoelectronic Applications</b> Do Kyung Hwang <i>Center of Opto-electronic Materials and Devices, Post-silicon Semiconductor Institute, KIST</i>
<b>FC3-H-2</b> 16:15~16:30	<b>Photosensitive Complementary Inverters Comprised of n-channel ReS<sub>2</sub> and p-channel CNT Field Effect Transistors</b> Jinheon Jeong, Seung Gi Seo, Seung Yeob Kim, Ajit Kumar, Mishra Dhananjay, and Sung Hun Jin <i>Department of Electronic Engineering, Incheon National University</i>
<b>FC3-H-3</b> 16:30~16:45	<b>Electrochromic Device Based Novel Spatial Light Modulator (SLM)</b> Yubin Song, Myungjun Kim, Chuljun Lee, Youngho Seo, and Daeseok Lee <i>Department of Electronic Materials Engineering, Kwangwoon University</i>
<b>FC3-H-4</b> 16:45~17:00	<b>Understanding NBIS Mechanism of a-IGZO TFTs by Pulsed Stress Measurements Using Various Voltage and Light Pulse Widths</b> Youngjoon Choi, Kihwan Kim, Suhyun Kim, and Saeroonter Oh <i>Department of Electrical Engineering, Hanyang University</i>
<b>FC3-H-5</b> 17:00~17:15	<b>Bias Stress Instability in Multi-layered MoTe<sub>2</sub> Field Effect Transistors under Pulse Mode Operation</b> Seung Gi Seo, Woong Jin Noh, Hyeon Bin Ahn, Minwoo Park, and Sung Hun Jin <i>Department of Electronic Engineering, Incheon National University</i>
<b>FC3-H-6</b> 17:15~17:30	<b>Gate Induced Drain Leakage Current (GIDL) Behaviors in Multi-layered MoTe<sub>2</sub> Field Effect Transistors</b> Seung Gi Seo, Youngho Park, Sungha Kim, Young Eun Sim, and Sung Hun Jin <i>Department of Electronic Engineering, Incheon National University</i>